

BLA6H0912L-1000; BLA6H0912LS-1000

LDMOS avionics power transistor

Rev. 1 — 4 November 2013

Objective data sheet

1. Product profile

1.1 General description

1000 W LDMOS pulsed power transistor intended for TCAS and IFF applications at 1030 MHz.

Table 1. Test information

Typical RF performance at $T_{case} = 25\text{ }^{\circ}\text{C}$; $t_p = 50\text{ }\mu\text{s}$; $\delta = 2\text{ }\%$; $I_{DQ} = 200\text{ mA}$; in a class-AB production test circuit.

Test signal	f (MHz)	V _{DS} (V)	P _L (W)	G _p (dB)	η_D (%)	t _r (ns)	t _f (ns)
pulsed RF	1030	50	1000	16	52	11	5

1.2 Features and benefits

- Easy power control
- Integrated ESD protection
- High flexibility with respect to pulse formats
- Excellent ruggedness
- High efficiency
- Excellent thermal stability
- Designed for broadband operation (960 MHz to 1215 MHz)
- Internally matched for ease of use
- Compliant to Directive 2002/95/EC, regarding Restriction of Hazardous Substances (RoHS)

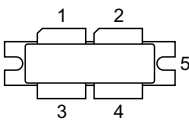
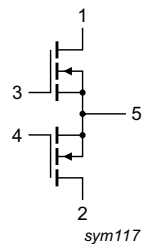
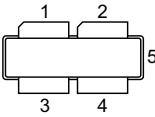
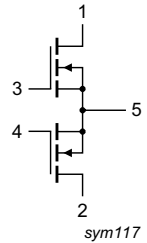
1.3 Applications

- 1000 W LDMOS pulsed power transistor intended for TCAS and IFF applications in the 1030 MHz to 1090 MHz frequency range



2. Pinning information

Table 2. Pinning

Pin	Description	Simplified outline	Graphic symbol
BLA6H0912L-1000 (SOT539A)			
1	drain1		
2	drain2		
3	gate1		
4	gate2		
5	source		
BLA6H0912LS-1000 (SOT539B)			
1	drain1		
2	drain2		
3	gate1		
4	gate2		
5	source		

[1] Connected to flange.

3. Ordering information

Table 3. Ordering information

Type number	Package		
	Name	Description	Version
BLA6H0912L-1000	-	flanged balanced ceramic package; 2 mounting holes; 4 leads	SOT539A
BLA6H0912LS-1000	-	earless flanged balanced ceramic package; 4 leads	SOT539B

4. Limiting values

Table 4. Limiting values

In accordance with the Absolute Maximum Rating System (IEC 60134).

Symbol	Parameter	Conditions	Min	Max	Unit
V_{DS}	drain-source voltage		-	100	V
V_{GS}	gate-source voltage		-0.5	+13	V
T_{stg}	storage temperature		-65	+150	°C
T_j	junction temperature	[1]	-	225	°C

[1] Continuous use at maximum temperature will affect reliability.

5. Thermal characteristics

Table 5. Thermal characteristics

Symbol	Parameter	Conditions	Typ	Unit
$Z_{th(j-c)}$	transient thermal impedance from junction to case	$T_{case} = 85\text{ }^{\circ}\text{C}; P_L = 1000\text{ W}$		
		$t_p = 50\text{ }\mu\text{s}; \delta = 2\%$	0.011	K/W
		$t_p = 100\text{ }\mu\text{s}; \delta = 10\%$	0.021	K/W
		$t_p = 200\text{ }\mu\text{s}; \delta = 10\%$	0.025	K/W
		$t_p = 300\text{ }\mu\text{s}; \delta = 10\%$	0.027	K/W
		$t_p = 2.4\text{ ms}; \delta = 6.4\%$	<tbid>	K/W

6. Characteristics

Table 6. DC characteristics

$T_j = 25\text{ }^{\circ}\text{C}$; per section unless otherwise specified.

Symbol	Parameter	Conditions	Min	Typ	Max	Unit
$V_{(BR)DSS}$	drain-source breakdown voltage	$V_{GS} = 0\text{ V}; I_D = 4\text{ mA}$	104.5	-	-	V
$V_{GS(th)}$	gate-source threshold voltage	$V_{DS} = 10\text{ V}; I_D = 270\text{ mA}$	1.4	1.8	2.4	V
I_{DSS}	drain leakage current	$V_{GS} = 0\text{ V}; V_{DS} = 50\text{ V}$	-	-	3	μA
I_{DSX}	drain cut-off current	$V_{GS} = V_{GS(th)} + 3.75\text{ V}; V_{DS} = 10\text{ V}$	35	-	-	A
I_{GSS}	gate leakage current	$V_{GS} = 11\text{ V}; V_{DS} = 0\text{ V}$	-	-	300	nA
g_{fs}	forward transconductance	$V_{DS} = 10\text{ V}; I_D = 400\text{ mA}$	2.3	-	-	S
$R_{DS(on)}$	drain-source on-state resistance	$V_{GS} = V_{GS(th)} + 3.75\text{ V}; I_D = 14\text{ A}$	-	-	120	m Ω

Table 7. RF characteristics

Test signal: pulsed RF; $t_p = 50\text{ }\mu\text{s}; \delta = 2\%$; RF performance at $V_{DS} = 50\text{ V}; I_{Dq} = 200\text{ mA}$; $f = 1030\text{ MHz}$; $T_{case} = 25\text{ }^{\circ}\text{C}$; unless otherwise specified, in a class-AB production test circuit.

Symbol	Parameter	Conditions	Min	Typ	Max	Unit
V_{DS}	drain-source voltage	$P_L = 1000\text{ W}$	-	-	50	V
G_p	power gain	$P_L = 1000\text{ W}$	<tbid>	16	-	dB
RL_{in}	input return loss	$P_L = 1000\text{ W}$	-	-12	<tbid>	dB
η_D	drain efficiency	$P_L = 1000\text{ W}$	<tbid>	52	-	%
$P_{droop(pulse)}$	pulse droop power	$P_L = 1000\text{ W}$	-	0	0.3	dB
t_r	rise time	$P_L = 1000\text{ W}$	-	11	30	ns
t_f	fall time	$P_L = 1000\text{ W}$	-	5	30	ns

7. Test information

7.1 Ruggedness in class-AB operation

The BLA6H0912L-1000 and the BLA6H0912LS-1000 are capable of withstanding a load mismatch corresponding to $VSWR = 5 : 1$ through all phases under the following conditions: $V_{DS} = 50\text{ V}; I_{Dq} = 200\text{ mA}; P_L = 1000\text{ W}; t_p = 50\text{ }\mu\text{s}; \delta = 2\%; f = 1030\text{ MHz}$.

7.2 Impedance information

Table 8. Typical impedance

Typical values per section unless otherwise specified.

f (MHz)	Z_S (Ω)	Z_L (η_D) (Ω)	Z_L (G_p) (Ω)
950	$1.12 - j2.27$	$0.60 + j0.21$	$0.62 - j0.02$
1000	$1.39 - j2.69$	$0.54 + j0.08$	$0.66 - j0.06$
1050	$1.79 - j2.79$	$0.40 + j0.03$	$0.52 - j0.28$
1100	$2.44 - j2.72$	$0.41 - j0.12$	$0.67 - j0.29$
1150	$1.68 - j2.52$	$0.49 - j0.21$	$0.53 - j0.35$
1200	$4.68 - j2.97$	$0.36 - j0.30$	$0.57 - j0.40$

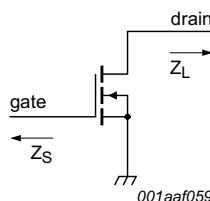
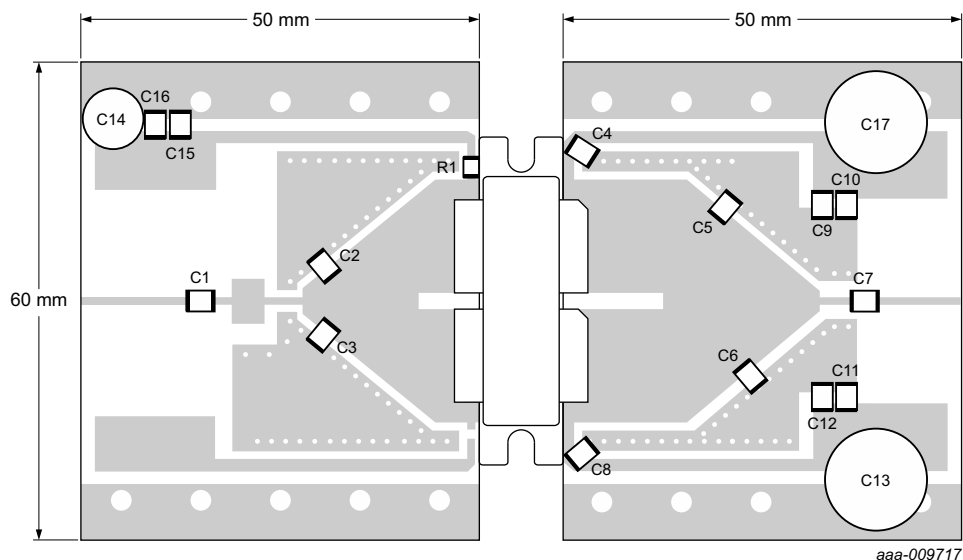


Fig 1. Definition of transistor impedance

7.3 Test circuit information



Printed-Circuit Board (PCB) material: Rogers Duroid 6006 with $\epsilon_r = 6.15$ and thickness = 0.64 mm.

See [Table 9](#) for list of components.

Fig 2. Component layout

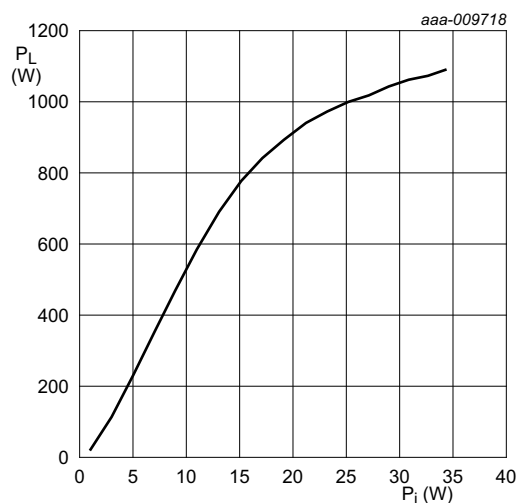
Table 9. List of componentsSee [Figure 2](#) for component layout.

Component	Description	Value	Remarks
C1, C7, C16	multilayer ceramic chip capacitor	33 pF	[1]
C2, C3	multilayer ceramic chip capacitor	3.6 pF	[1]
C4, C8	multilayer ceramic chip capacitor	33 pF	[1]
C5, C6	multilayer ceramic chip capacitor	3.3 pF	[1]
C9, C12	multilayer ceramic chip capacitor	220 nF	AVX
C10, C11	multilayer ceramic chip capacitor	4.7 μ F	Murata
C13, C17	electrolytic capacitor	22 μ F, 200 V	
C14	electrolytic capacitor	4.7 μ F	
C15	multilayer ceramic chip capacitor	1 nF	[1]
R1	SMD resistor	9.1 Ω	SMD 0603

[1] American Technical Ceramics type 100B or capacitor of same quality.

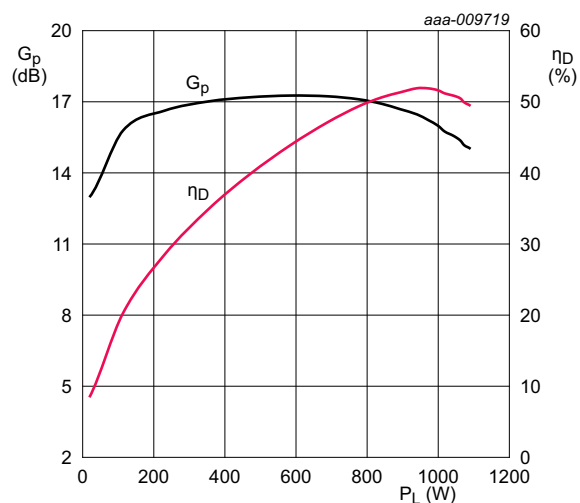
7.4 Graphical data

7.4.1 Pulsed CW



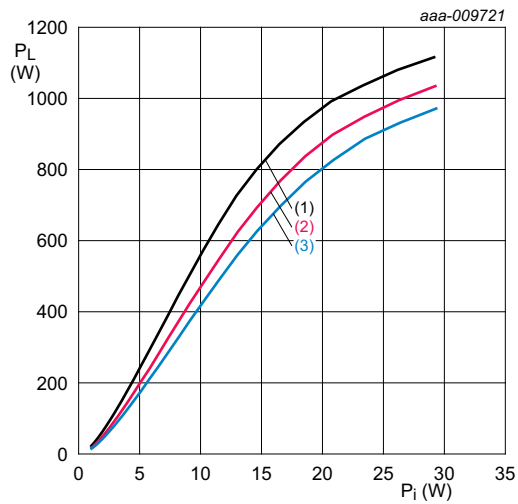
$V_{DS} = 50$ V; $I_{DQ} = 200$ mA; $f = 1030$ MHz; $t_p = 50$ μ s;
 $\delta = 2$ %.

Fig 3. Output power as a function of input power; typical values



$V_{DS} = 50$ V; $I_{DQ} = 200$ mA; $f = 1030$ MHz; $t_p = 50$ μ s;
 $\delta = 2$ %.

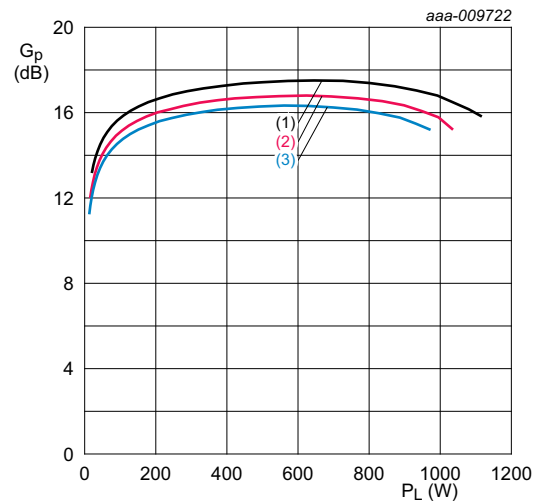
Fig 4. Power gain and drain efficiency as function of output power; typical values



$V_{DS} = 50 \text{ V}$; $I_{DQ} = 200 \text{ mA}$; $f = 1030 \text{ MHz}$; $t_p = 50 \text{ } \mu\text{s}$;
 $\delta = 2 \text{ } \%$.

- (1) $T_{case} = 20 \text{ } ^\circ\text{C}$
- (2) $T_{case} = 50 \text{ } ^\circ\text{C}$
- (3) $T_{case} = 70 \text{ } ^\circ\text{C}$

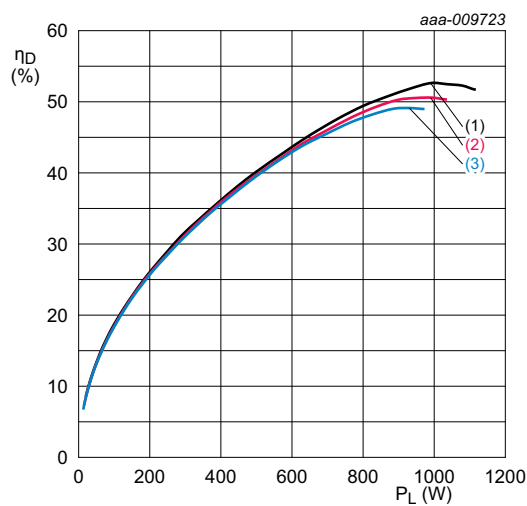
Fig 5. Output power as a function of input power; typical values



$V_{DS} = 50 \text{ V}$; $I_{DQ} = 200 \text{ mA}$; $f = 1030 \text{ MHz}$; $t_p = 50 \text{ } \mu\text{s}$;
 $\delta = 2 \text{ } \%$.

- (1) $T_{case} = 20 \text{ } ^\circ\text{C}$
- (2) $T_{case} = 50 \text{ } ^\circ\text{C}$
- (3) $T_{case} = 70 \text{ } ^\circ\text{C}$

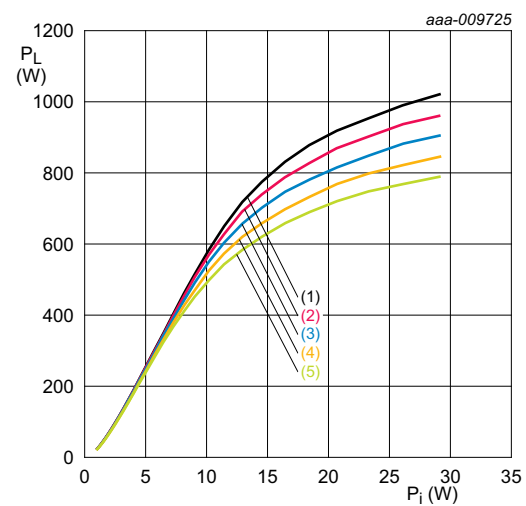
Fig 6. Power gain as a function of output power; typical values



$V_{DS} = 50 \text{ V}$; $I_{DQ} = 200 \text{ mA}$; $f = 1030 \text{ MHz}$; $t_p = 50 \text{ } \mu\text{s}$;
 $\delta = 2 \text{ } \%$.

- (1) $T_{case} = 20 \text{ } ^\circ\text{C}$
- (2) $T_{case} = 50 \text{ } ^\circ\text{C}$
- (3) $T_{case} = 70 \text{ } ^\circ\text{C}$

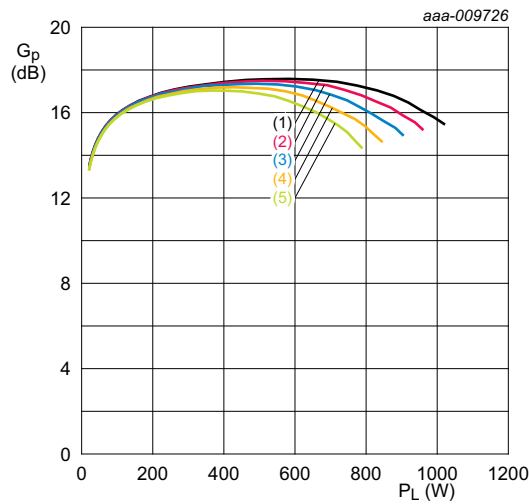
Fig 7. Drain efficiency as a function of output power; typical values



$I_{DQ} = 200 \text{ mA}$; $t_p = 50 \text{ } \mu\text{s}$; $\delta = 2 \text{ } \%$.

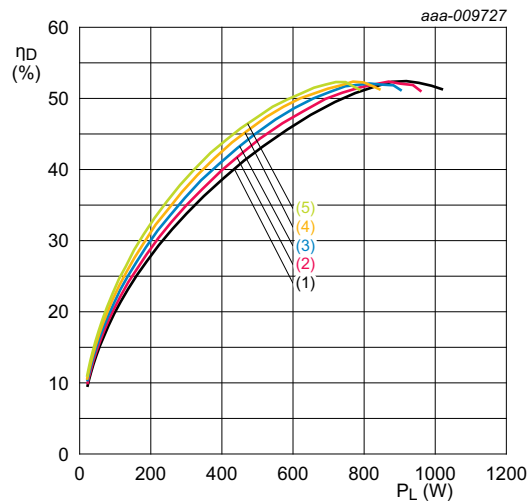
- (1) $V_{DS} = 50 \text{ V}$
- (2) $V_{DS} = 48 \text{ V}$
- (3) $V_{DS} = 46 \text{ V}$
- (4) $V_{DS} = 44 \text{ V}$
- (5) $V_{DS} = 42 \text{ V}$

Fig 8. Output power as a function of input power; typical values



- $I_{Dq} = 200 \text{ mA}$; $t_p = 50 \text{ }\mu\text{s}$; $\delta = 2 \text{ }\%$.
- (1) $V_{DS} = 50 \text{ V}$
 - (2) $V_{DS} = 48 \text{ V}$
 - (3) $V_{DS} = 46 \text{ V}$
 - (4) $V_{DS} = 44 \text{ V}$
 - (5) $V_{DS} = 42 \text{ V}$

Fig 9. Power gain as a function of output power; typical values



- $I_{Dq} = 200 \text{ mA}$; $t_p = 50 \text{ }\mu\text{s}$; $\delta = 2 \text{ }\%$.
- (1) $V_{DS} = 50 \text{ V}$
 - (2) $V_{DS} = 48 \text{ V}$
 - (3) $V_{DS} = 46 \text{ V}$
 - (4) $V_{DS} = 44 \text{ V}$
 - (5) $V_{DS} = 42 \text{ V}$

Fig 10. Drain efficiency as a function of output power; typical values

8. Package outline

Flanged balanced ceramic package; 2 mounting holes; 4 leads

SOT539A

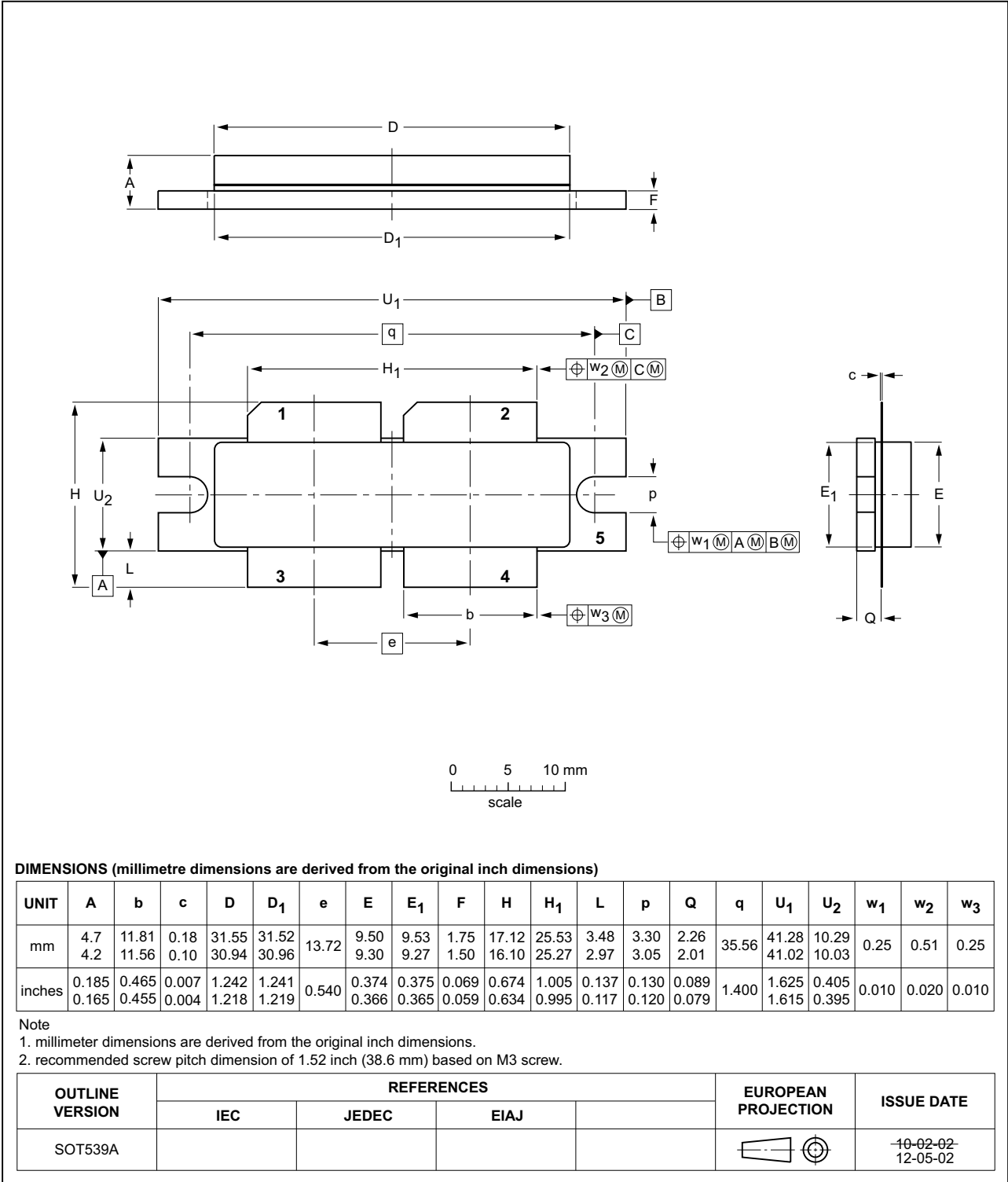


Fig 11. Package outline SOT539A

Earless flanged balanced ceramic package; 4 leads

SOT539B

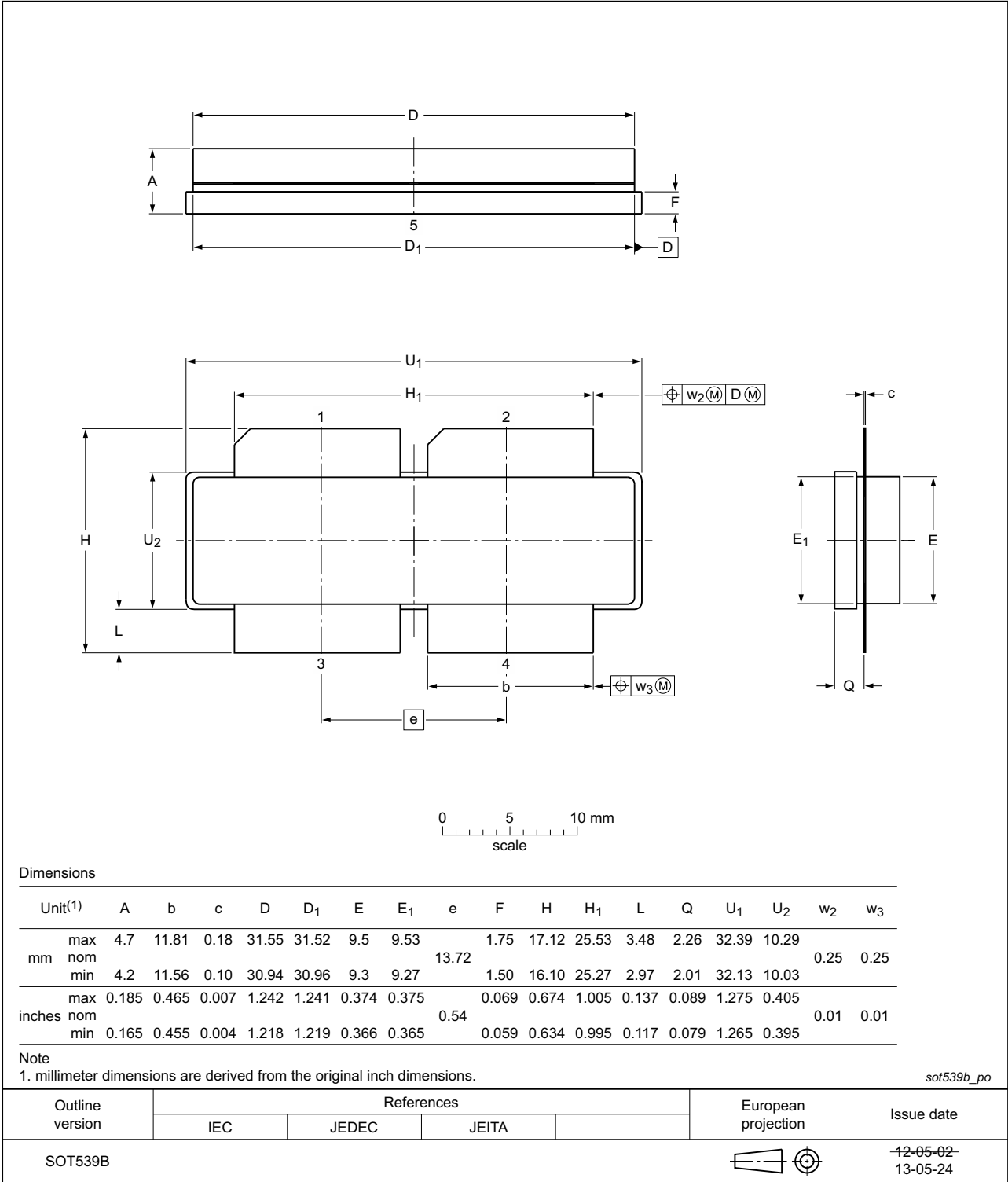


Fig 12. Package outline SOT539B

9. Handling information

CAUTION



This device is sensitive to ElectroStatic Discharge (ESD). Observe precautions for handling electrostatic sensitive devices.

Such precautions are described in the *ANSI/ESD S20.20*, *IEC/ST 61340-5*, *JESD625-A* or equivalent standards.

10. Abbreviations

Table 10. Abbreviations

Acronym	Description
CW	Continuous Wave
ESD	ElectroStatic Discharge
IFF	Identification Friend or Foe
LDMOS	Laterally Diffused Metal-Oxide Semiconductor
SMD	Surface Mounted Device
TCAS	Traffic Collision Avoidance System
VSWR	Voltage Standing-Wave Ratio

11. Revision history

Table 11. Revision history

Document ID	Release date	Data sheet status	Change notice	Supersedes
BLA6H0912L-1000_0912LS-1000 v.1	20131104	Objective data sheet	-	-

12. Legal information

12.1 Data sheet status

Document status ^{[1][2]}	Product status ^[3]	Definition
Objective [short] data sheet	Development	This document contains data from the objective specification for product development.
Preliminary [short] data sheet	Qualification	This document contains data from the preliminary specification.
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[2] The term 'short data sheet' is explained in section "Definitions".

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